Metric between buckling structures and elastic properties in physisorbed polymer-tethered lipid monolayers

Amanda P. Siegel,^{*a*} Noor F. Hussain,^{*a*} Merrell Johnson^{*b*} and Christoph A. Naumann^{*a**}

^a Department of Chemistry and Chemical Biology, Indiana University-Purdue University Indianapolis, Indianapolis, IN 46202-3274, USA. Tel:317-274-6872; Email: canauman@iupui.edu

^b Department of Physics, Indiana University-Purdue University Indianapolis, Indianapolis, IN 46202-3274, USA.



Figure S1. (A) Histogram of heights determined at each pixel for 10 mol% DSPE-PEG monolayer. (B) Cumulative histogram of pixel heights. (B-insert) AFM micrograph of 10 mol% DSPE-PEG5000 with bearing area cutoff shown by color: fraction to the left of bearing area cutoff arrow indicated in AFM micrograph in blue; fraction to the right indicated in red.



Figure S2. Analysis of section width determination. A) Typical section width analysis for 10% DSPE-PEG5000 monolayer. B) AFM micrograph showing location of width determination. Lines between sections = 349 nm. C Histogram of data acquired from 10% DSPE-PEG monolayer. Mean = 350 nm.



Figure S32. SOPC bilayers with 5 (A), 10 (B), 30 (C) and 40 (D) mol% DSPE-PEG5000. Scale bar = $10 \mu m$.